

MCF Lunch Seminar Series 2018

Giesecke Engineering Research Building (ERB 154)

April 19

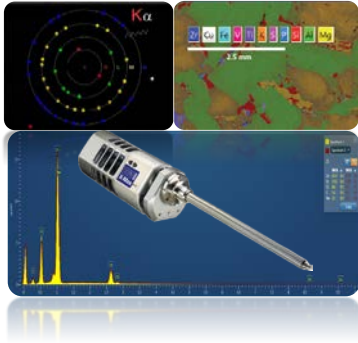
12:00-1:00PM

An Introduction to Energy Dispersive X-ray (EDX) and its Applications

EDS (Energy Dispersive Spectroscopy) is an established technique used to characterize the elemental composition of a sample under the beam of an electron microscope. This seminar will discuss the basic principles and how SDD hardware detects and measures the X-rays and converts them into signals which can be used by software to provide accurate and reliable EDS analysis.

Speaker: Dr. Winson Kuo

Register as seats are limited : winsonkuo@tamu.edu



April 23

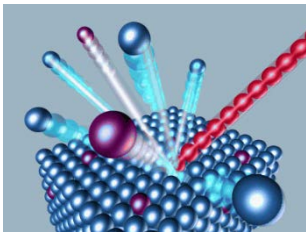
12:00-1:00PM

Secondary Ion Mass Spectrometry (SIMS): Surface elemental and molecular analysis, depth profiling and imaging

SIMS is highly sensitive and capable method of analyzing practically any ionizable element from both inorganic and organic samples, down to low parts-per-billion levels. The technique is used primarily in the semiconductor industry, although recently Cluster SIMS became increasingly important for biological applications by providing information about trace elements, isotopes, and molecular composition.

Speaker: Dr. Stanislav Verkhoturov

Register as seats are limited : verkhoturov@tamu.edu



Light refreshments will be provided

Free Parking